

Notice of References Cited	Application/Control No. 10/630,001	Applicant(s)/Patent Under Reexamination TEIWES ET AL.	
	Examiner John B. Strege	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,322,216	11-2001	Yee et al.	351/210
*	B	US-5,311,879	05-1994	Yamada et al.	600/558
*	C	US-5,098,426	03-1992	Sklar et al.	606/5
	D	US-			
	E	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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